

| | | | | |
|-----------------------------------|--|---------------------------------------|--|-------------|
| Notice of References Cited | | Application/Control No. 09/830,831 | Applicant(s)/Patent Under Reexamination BUDNIK, BERNHARD | |
| | | Examiner TAN TRINH | Art Unit 2684 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| | A | US-6,292,662 B1 | 09-2001 | Ziv et al. | 455/445 |
| | B | US-5,706,282 | 01-1998 | Chung, Min I. | 370/280 |
| | C | US-5,806,002 A | 09-1998 | Wiatrowski et al. | 455/512 |
| | D | US-6,785,267 B1 | 08-2004 | Knappe, Michael E. | 370/353 |
| | E | US-5,257,401 A | 10-1993 | Dahlin et al. | 455/436 |
| | F | US-6,343,113 B1 | 01-2002 | Shu, Linmei | 379/24 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.